

# Fluorescent Speckle Microscopy

Stephen W. Carmichael and Wilma L. Lingle,<sup>1</sup>  
 Mayo Clinic  
 stephen.carmichael@mayo.edu

Whereas too much of a good thing can be bad, too little of a good thing can be good. In this case, the accidental dilution of X-rhodamine tubulin injected into living cells resulted in a heterogeneous labeling of microtubules, rather than visualization of continuous structures. This heterogeneous labeling rendered a speckled image, hence the term fluorescent speckle microscopy (FSM) was introduced. It turns out that FSM yields particularly useful information on dynamic events within living cells, for example the assembly and disassembly of microtubules.

There are two recent reviews of FSM by Clare Waterman-Storer and Gaudenz Danuser, one emphasizing the biologic applications of the technique<sup>2</sup>, the other emphasizing the quantitative aspects.<sup>3</sup> For their purposes, they defined a "speckle" as a diffraction-limited region of the image that is significantly brighter than its immediate environment. It can be calculated from the point-spread function (which is determined by the numerical aperture of the lens) that optimally a diffraction-limited region of about 250 nm can be imaged. Within such a region, about 450 tubulin dimers (components of a microtubule) are present. If more than 20% of the dimers along the length of a microtubule are tagged with a fluorescent dye, the microtubule appears to be continuously labeled. If a smaller percentage (1-2%) is labeled, the microtubule is speckled. It was demonstrated that the appearance of speckles over time is indicative of microtubule assembly, whereas the disappearance of speckles is evidence of disassembly. These dynamic events can be observed quantitatively with good spatial and temporal resolution by FSM. Even assembly at one end and simultaneous disassembly at the other (referred to as "treadmilling") can be examined to determine if the underlying mechanism is mediated by microtubule motor proteins or tubulin exchange at the ends of the microtubules.

In addition to studies of microtubule assembly and motion, Danuser and Waterman-Storer reviewed several other applications of FSM.

These include, but are not limited to, dynamic studies of microtubules in mitosis and in neurons, f-actin in migrating cells, and analyzing microtubule-associated proteins. Conjugating target proteins with Green Fluorescent Protein (GFP) also is useful in FSM. It was suggested that binding and dissociation dynamics or single molecule fluorescence analysis of many proteins might be studied *in vivo* and *in vitro*.

Methods of analysis of FSM currently include the use of kymographs to determine the velocity of speckle movement and laborious hand tracking of a small subset of speckles. Although these methods had provided us with a deeper understanding of the dynamics of polymer kinetics, their use is limited and does not fully exploit the information inherent in time lapse FSM. Waterman-Storer and Danuser suggested that the full potential of FSM would become available once the specialized computational tools are developed for the statistical analysis of speckle translocation and intensity fluctuation. The task of tracking over half a million moving speckles is daunting, but not out of reach for the technology in the future.

Future prospects for FSM are bright, particularly because it can be applied to other fluorescence microscopy technology. For example, FSM can be combined with spinning disk confocal microscopy, total internal reflection fluorescent microscopy, and multi-spectral microscopy. Waterman-Storer and Danuser envision the use of FSM technology to analyze the kinetics of important molecules in many biologic processes, as well as material science applications. It will be exciting to see the information that can be gleaned with this technology that offers so much spatial and kinetic information! ■

## References:

- 1 The authors gratefully acknowledge Dr. Clare Waterman-Storer for reviewing this article.
- 2 Waterman-Storer, C.C., and G. Danuser, New directions for fluorescent speckle microscopy, *Current Biology* 12:R633-R640, 2002.
- 3 Danuser, G., and C.M. Waterman-Storer, Quantitative fluorescent speckle microscopy: Where it came from and where it is going, *J. Microscopy* 211:191-207, 2003.

## INDEX OF ARTICLES

<b>Fluorescent Speckle Microscopy</b> .....	<b>3</b>	<b>Lens Cleaning - Best Practices Review</b> .....	<b>42</b>
<i>Stephen W. Carmichael and Wilma L. Lingle, Mayo Clinic</i>		<i>C.V. Duke</i>	
<b>The Nematode <i>Caenorhabditis elegans</i></b>		<b>Use of Fishing Weight Putty for Quickly</b>	
<b>A Model Animal "Made for Microscopy"</b> .....	<b>8</b>	<b>Mounting SEM Specimens</b> .....	<b>45</b>
<i>David H. Hall, Albert Einstein College of Medicine</i>		<i>Hans Stephenson and Mark Gabel, Black Hills State University</i>	
<b>Digital Movies for Others to See</b> .....	<b>14</b>	<b>A Homemade Vacuum Forceps For Mounting</b>	
<i>Jerry Sedgewick, University of Minnesota</i>		<b>Small SEM Samples</b> .....	<b>45</b>
<b>Microwave Mechanisms - The Energy/Heat Dichotomy</b> .....	<b>18</b>	<i>Sol Seepsenwol, University of Wisconsin</i>	
<i>J.J. Galvez†, R.T. Giberson‡, R.D. Cardiff†</i>		<b>Industry News</b> .....	<b>48</b>
<i>†University of California, Davis, ‡Ted Pella, Inc.</i>		<b>NetNotes</b> .....	<b>50</b>
<b>Photoshop and 12-bit Digital Microscope Camera Images</b> ....	<b>24</b>	<b>Index of Advertisers</b> .....	<b>54</b>
<i>Brent Neal, Reindeer Graphics, Inc.</i>			
<b>Guidance for Choosing When to Use Electron and/or</b>			
<b>Light Microscopy and Related ASTM E4 Standards</b> .....	<b>26</b>		
<i>R. C. Nester, International Steel Group, ISG Research</i>			
<b>The Role of Microscopy in Indoor Air Quality Investigations</b> .....	<b>28</b>		
<i>R.B. Simmons, Georgia State University</i>			
<b>How to Promote a Facility In Order to Increase Use, Acquire New</b>			
<b>Equipment and, as a Result, Increase Revenue</b> .....	<b>32</b>		
<i>Elaine Humphrey, University of British Columbia</i>			
<b>TEM Specimen Preparation Technique</b>			
<b>for Small Semiconductor Devices</b> .....	<b>38</b>		
<i>M. Hudson, J. Benedict, and P. Flaitz, IBM Microelectronics</i>			

## ABOUT THE COVER

### C. elegans trapped in THE MATRIX

Artwork and original light micrograph by Robyn Lints, reworked in Photoshop; see D.H. Hall this issue, Fig. 7, page 12. An homage to the movie poster by Jason Giovannelli for The Matrix, the Warner Bros. motion picture, producers Joel Silver, Barrie Osborne and Andrew Mason.

Intuitive Operation.  
Outstanding Productivity.  
Expert Support.

https://doi.org/10.1017/S15192500051529 Published online by Cambridge University Press



- **X-RAY ANALYSIS**
- **X-RAY DETECTORS**
- **IMAGE ANALYSIS**
- **EBSD BY HKL**

We understand how valuable your data and time are. That's why our systems are designed with a simple, intuitive user interface, making it easy for even novice users to quickly get up and running with minimal training time.

We take productivity a step further with software to reliably automate routine analysis tasks and generate concise reports.

We have a superior team of field service personnel, and an applications lab staffed by experienced microscopists to offer assistance with data interpretation.

Visit our website at [www.pgt.com](http://www.pgt.com) or contact us at (609) 924-7310 for more information. Put us to work for you today!



Princeton Gamma-Tech  
1026 Route 518  
Rocky Hill, NJ 08553

Toll Free: (800) 229-7484  
Tel: (609) 924-7310  
Fax: (609) 924-1729

e-mail: [sales@pgt.com](mailto:sales@pgt.com)

[www.pgt.com](http://www.pgt.com)



## COMING EVENTS

- ✓ **Focus on Microscopy 2004**  
April 4-7, 2004, Philadelphia, PA  
[www.focusonmicroscopy.org](http://www.focusonmicroscopy.org)
- ✓ **Materials Research Society**  
April 12-16, 2004, San Francisco, CA  
[info@mrs.org](mailto:info@mrs.org)
- ✓ **SCANNING 2004**  
April 27-29, 2004, Washington, DC  
[www.scanning.org](http://www.scanning.org)
- ✓ **Asia-Pacific Congress on Electron Microscopy**  
June 7-11, 2004, Kanazawa, Japan  
[keih@kanazawa-med.ac.jp](mailto:keih@kanazawa-med.ac.jp)
- ✓ **Lehigh Microscopy Schools**  
June 6, 2004, Introduction to SEM and EDS  
June 7-11, 2004, SEM and X-ray Microanalysis  
June 14-18, 2004, Problem Solving with the SEM and EDS  
June 14-18, 2004, Quantitative EDS of Bulk Spec. & Particles  
June 14-17, 2004, Analytical EM for TEM Specimens  
June 14-17, 2004, Characterization of Nanostructures  
June 14-17, 2004, FIB Instrumentation and Applications  
June 14-17, 2004, Particle Characterization, Prep. & Analysis  
June 14-17, 2004, AFM and Other Scanned Probe Microscopies  
[sharon.coe@lehigh.edu](mailto:sharon.coe@lehigh.edu)
- ✓ **12th Int'l. Congress of Histochemistry and Cytochemistry**  
July 24-29, 2004, LaJolla, CA  
[www.ifschc.org/index2004.html/](http://www.ifschc.org/index2004.html/)
- ✓ **Cryo-HRSEM/STEM/TEM**  
July 28-30, 2004, Atlanta, GA  
[rapkari@emory.edu](mailto:rapkari@emory.edu)
- ✓ **Microscopy and Microanalysis 2004**  
August 1-5, 2004, Savannah, GA  
[www.msa.microscopy.com](http://www.msa.microscopy.com)
- ✓ **EMC 2004 (former EUREM)**  
August 22-27, 2004, Antwerp, Belgium  
[www.emc2004.be](http://www.emc2004.be)
- ✓ **Society for Neuroscience**  
October 23-28, 2004  
[info@sfn.org](mailto:info@sfn.org)
- 2005**
- ✓ **Materials Research Society**  
April 12-16, 2005, San Francisco, CA  
[info@mrs.org](mailto:info@mrs.org)
- ✓ **Scanning 2005**  
May 5-7, 2005, Monterey, CA  
[scanning@fams.org](mailto:scanning@fams.org)
- ✓ **Microscopy and Microanalysis 2005**  
July 31- August 4, 2005, Honolulu, HA  
[www.msa.microscopy.com](http://www.msa.microscopy.com)
- ✓ **Materials Research Society**  
November 29- December 3, 2004, Boston, MA  
[info@mrs.org](mailto:info@mrs.org)
- ✓ **American Society for Cell Biology 2003**  
December 4-8, 2004, Washington, DC  
[www.ascb.org](http://www.ascb.org)
- 2006**
- ✓ **Microscopy and Microanalysis 2006**  
August 6-10, 2006, Chicago, IL  
[www.msa.microscopy.com](http://www.msa.microscopy.com)  
Please check the "Calendar of Meetings and Courses" in the MSA journal "Microscopy and Microanalysis" for more details and a much larger listing of meetings and courses.

## MICROSCOPY TODAY

The objective of this publication is simply to provide material of interest and value to working microscopists!

The publication is owned by the Microscopy Society of America (MSA) and is produced six times each year in odd months, alternating with MSA's peer-reviewed, scientific journal *Microscopy and Microanalysis*. We greatly appreciate article and material contributions from our readers—"users" as well as manufacturers/suppliers. The only criterion is that the subject matter be of interest to a reasonable number of working microscopists. *Microscopy Today* has authors from many disparate fields in both biological and materials sciences, each field with its own standards. Therefore *MT* does not have a rigid set of style instructions and encourages authors to use their own style, asking only that the writing be clear, informative, and accurate. Length: typical article length is 1,500 to 2,000 words plus images. Longer articles will be considered. Short notes are encouraged for our Microscopy 101 section.

## MICROSCOPY TODAY

Ron Anderson, Editor

[ron.anderson@attglobal.net](mailto:ron.anderson@attglobal.net)

José Mascorro, Technical Editor

[jmascor@tulane.edu](mailto:jmascor@tulane.edu)

Dale Anderson, Art Director

[dale.anderson@attglobal.net](mailto:dale.anderson@attglobal.net)

Regular Mail to:

1001 Starkey Road, #374

Largo, FL 33771

Courier Mail to:

Starkey Road address for now

Telephones:

1-(727)507-7101 • Fax: (727)507-7102 • Cell: (914) 453-2917

e-Mail:

[microscopytoday@tampabay.rr.com](mailto:microscopytoday@tampabay.rr.com)

WWW Page:

<http://www.microscopy-today.com>

**Total Circulation: 16,004**

**Disclaimer:** By submitting a manuscript to *Microscopy Today*, the author warrants that the article is original (or that the author has the right to use any material copyrighted by others). The use of trade names, trademarks, etc., does not imply that these names lack protection by relevant laws and regulations. *Microscopy Today*, the Microscopy Society of America, and any other societies stated, cannot be held responsible for opinions, errors, or for any consequences arising from the use of information contained in *Microscopy Today*. The appearance of advertising in *Microscopy Today* does not constitute an endorsement or approval by the Microscopy Society of America of the quality or value of the products advertised or any of the claims, data, conclusions, recommendations, procedures, results or any information found in the advertisements. While the contents of this magazine are believed to be accurate at press time, neither the Microscopy Society of America, the editors, nor the authors can accept legal responsibility for errors or omissions.

© Copyright, 2004, The Microscopy Society of America. All rights reserved.



# Scandium

Universal SEM imaging platform

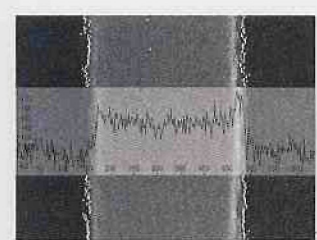
**Now available - Scandium - Soft Imaging System's new universal imaging platform for all types of SEM and FIB machines**


The concept behind this software as well as its architecture have been determined by the demands, needs and customary workflows in the scanning-microscopy field. The software is available in various expansion levels.

**Scandium** raises the bar with its enormous range of functions, user-friendliness, intuitive use and a modular approach offering tremendous flexibility.

**Scandium** will operate the microscope (provided the microscope is properly equipped), control the motorized stage, transfer images and read out acquisition parameters. Subsequently, the images can be processed, analyzed and combined with the EDS spectra in **Scandium**. In order to manage all results, **Scandium** offers an integrated archive and integrated report generator for professional documentation. **Scandium's** greatest feature is that it can automate the entire SEM lab workflow.

## Turning visions into realities



Digital Solutions for Imaging and Microscopy  
**Soft Imaging System** 

For detailed information please contact

**Soft Imaging System**  
info@soft-imaging.de  
www.soft-imaging.net/sem

North America (888) FIND SIS  
+1 (303) 234-9270  
Europe +49 (251) 79800-0  
Asia | Pacific +60 (3) 8313-1400